

#### **Feature**

- Precision MEMS process
- High performance, shielded, Micro-cavity structure
- Silicon substrate, 50Ω CPW output
- Au wire bonding, for MCM applications

## **Environmental Specifications**

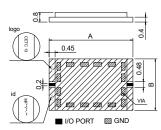
Operating Temperature	-55℃~+85℃	
Storage Temperature	-55°C∼+125°C	
Max. Input Power	35dBm	

# Electrical Specifications(T<sub>A</sub>=+25°C)

Parameter	Min.	Тур.	Max.	Unit
Center Freq. (f₀)	-	3.5	-	GHz
Pass Band	3.0	-	4.0	GHz
Ripple in Pass band	-	-	1	dB
Insertion Loss @ fo	-	-	1.8	dB
Return Loss	12	-	-	dB
	≥30@2.65GHz&4.4GHz			dB
Out of band	≥40@2.	dB		
Attenuation	≥60@DC~2GHz			dB
	≥60@5~	dB		
Group Delay Variation	≤1@3.0	ns		
Linear Phase	≤±10@3	0		

S2P file name: SiMF3R5\_1-8D2.s2p

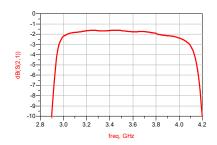
# **Outline Drawing**



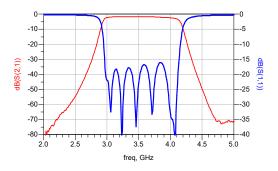
Cumbal	Value (mm)			
Symbol	Min.	Nominal	Max.	
А	6.9	-	7.0	
В	7.1	-	7.2	

# **Typical Test Curves**

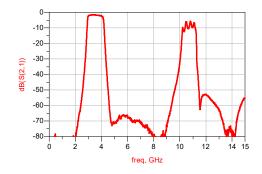
Insertion Loss VS Frequency (T<sub>A</sub>=25°C)



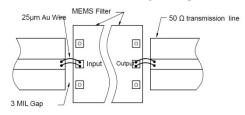
Insertion Loss & Return Loss VS Frequency (T<sub>A</sub>=25°C)



Broadband Insertion Loss VS Frequency (T<sub>A</sub>=25°C)

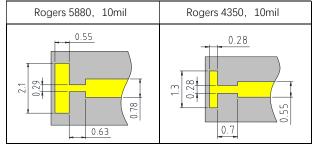


### **Recommended Assembly Diagrams**



### **Application Notes:**

- 1. The chip is back-metalized and can be die mounted with AuSn eutectic performs or with electrically conductive epoxy (for example ME8456).
- 2. The die should be assembled on carriers like Kovar or Mu-Cu which have same Coefficient of thermal expansion. (2.9ppm/ $^{\circ}$ C) with Silicon, thickness 0.2mm max.
- 3. Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.
- 4. Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers.
- 5. Recommended to use T structure as below for bonding.



6. If you have any questions, please contact us.